|                              | issue classification   | 10815111                       | Keexamination<br>LEE ET AL.  |                       |
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|                              | ORIGINAL               |                                | INTERNATIONAL CLASSIFICATION | CLASSIFICATION        |
| CLASS                        |                        | SUBCLASS                       | CLAIMED                      | NON-CLAIMED           |
| 702                          | 183                    |                                | G 0 6 F 19 / 00              |                       |
| S                            | CROSS REFERENCE(S)     | E(S)                           |                              |                       |
| CLASS                        | SUBCLASS (ONE SUBCLASS | LASS PER BLOCK)                |                              |                       |
| 340 524                      | 532                    | 539.26 539.29                  |                              |                       |
|                              |                        |                                |                              |                       |
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